L Number	Hits	Search Text	DB	Time stamp .
1	3461	(SEM or (scanning adj electron adj	USPAT;	2003/01/12 16:00
		microscop\$3)) and (imag\$3) and defect	US-PGPUB;	
		•	EPO; JPO;	•
			DERWENT; IBM TDB	
8	4556	(250/306,307,311,442.11)).CCLS.	USPAT;	2003/01/12 15:59
	3000	(250,500,501,511,412.111,7.0000.	US-PGPUB;	
!			EPO; JPO;	
į į			DERWENT;	
			IBM_TDB	
15	839	((SEM or (scanning adj electron adj	USPAT;	2003/01/12 16:00
		microscop\$3)) and (imag\$3) and defect) and	US-PGPUB;	
		(imag\$3 with defect)	EPO; JPO; DERWENT;	
			IBM TDB	
22	123	(((SEM or (scanning adj electron adj	USPAT;	2003/01/12 16:01
		microscop\$3)) and (imag\$3) and defect) and	US-PGPUB;	
		(imag\$3 with defect)) and magnif\$4	EPO; JPO;	
			DERWENT;	
		////CPM on /opening odi aliatura adi	IBM_TDB	2003/01/12 16:01
29	77	((((SEM or (scanning adj electron adj microscop\$3)) and (imag\$3) and defect) and	USPAT; US-PGPUB;	2003/01/12 16:01
1		(imag\$3 with defect)) and magnif\$4) and	EPO; JPO;	
		(monitor or screen)	DERWENT;	
			IBM_TDB	
36	72		USPĀT;	2003/01/12 16:01
		microscop\$3)) and (imag\$3) and defect) and	US-PGPUB;	
		(imag\$3 with defect)) and magnif\$4) and	EPO; JPO;	
		(monitor or screen)) and select\$3	DERWENT; IBM TDB	
43	23	 ((((((SEM or (scanning adj electron adj	USPAT;	2003/01/12 16:02
13	23	microscop\$3)) and (imag\$3) and defect) and	US-PGPUB;	2303,01,12 10.02
		(imag\$3 with defect)) and magnif\$4) and	EPO; JPO;	
		(monitor or screen)) and select\$3) and	DERWENT;	
		(select\$3 with area)	IBM_TDB	0000/65/55 55
50	22		USPAT;	2003/01/12 16:03
		microscop\$3)) and (imag\$3) and defect) and	US-PGPUB; EPO; JPO;	
		(imag\$3 with defect)) and magnif\$4) and (monitor or screen)) and select\$3) and	DERWENT;	
1		(select\$3 with area)) and display\$3	IBM TDB	
57	19	(((((((SEM or (scanning adj electron adj	USPAT;	2003/01/12 16:06
		microscop\$3)) and (imag\$3) and defect) and	US-PGPUB;	
		(imag\$3 with defect)) and magnif\$4) and	EPO; JPO;	
		(monitor or screen)) and select\$3) and	DERWENT;	
1		(select\$3 with area)) and display\$3) and ((mov\$3 or position\$3 or adjust\$3) with	IBM_TDB	
		(sample or stage or wafer or mask or		
		rectile or substrate))		
64	19	((((((((SEM or (scanning adj electron adj	USPAT;	2003/01/12 16:06
		microscop\$3)) and (imag\$3) and defect) and	US-PGPUB;	
		(imag\$3 with defect)) and magnif\$4) and	EPO; JPO;	
		(monitor or screen)) and select\$3) and	DERWENT;	
		(select\$3 with area)) and display\$3) and	IBM_TDB	
		((mov\$3 or position\$3 or adjust\$3) with (sample or stage or wafer or mask or		
		rectile or substrate))) and compar\$4		
71	19	(((((((((SEM or (scanning adj electron	USPAT;	2003/01/12 16:07
_	_,	adj microscop\$3)) and (imag\$3) and defect)	US-PGPUB;	
		and (imag\$3 with defect)) and magnif\$4)	EPO; JPO;	
		and (monitor or screen)) and select\$3) and	DERWENT;	
		(select\$3 with area)) and display\$3) and	IBM_TDB	
		((mov\$3 or position\$3 or adjust\$3) with		
		(sample or stage or wafer or mask or rectile or substrate))) and compar\$4) and		
		referenc\$3		
		1010101070	L	<u> </u>

78 14 ((((((((SEM or (scanning adj electron USPAT;	
	2003/01/12 16:09
adj microscop\$3)) and (imag\$3) and defect) US-PGPU	
and (imag\$3 with defect)) and magnif\$4) EPO; JP	1
and (monitor or screen)) and select\$3) and DERWENT	J
(select\$3 with area)) and display\$3) and IBM_TDB	
((mov\$3 or position\$3 or adjust\$3) with	
(sample or stage or wafer or mask or	
rectile or substrate))) and compar\$4) and	
referenc\$3) and (compar\$4 with referenc\$3)	
85	2003/01/12 16:10
adj microscop\$3)) and (imag\$3) and defect) US-PGPU	В;
and (imag\$3 with defect)) and magnif\$4) EPO; JP	0;
and (monitor or screen)) and select\$3) and DERWENT	;
(select\$3 with area)) and display\$3) and IBM TDB	
((mov\$3 or position\$3 or adjust\$3) with	
(sample or stage or wafer or mask or	
rectile or substrate))) and compar\$4) and	
referenc\$3) and (compar\$4 with	
referenc\$3)) and (superimpos\$4 or impos\$4)	
92 12 ((((((((((SEM or (scanning adj electron USPAT;	2003/01/12 16:11
adj microscop\$3)) and (imag\$3) and defect) US-PGPU	
and (imag\$3 with defect)) and magnif\$4) EPO; JP	
and (monitor or screen)) and select\$3) and DERWENT	Į.
(select\$3 with area)) and display\$3) and IBM TDB	1
((mov\$3 or position\$3 or adjust\$3) with	
(sample or stage or wafer or mask or	
rectile or substrate))) and compar\$4) and	
referenc\$3) and (compar\$4 with	
referenc\$3)) and (superimpos\$4 or	
impos\$4)) and stor\$4	2003/01/12 16:11
99 1 ((((((((((((((((((((((((((((((((((
electron adj microscop\$3)) and (imag\$3) US-PGPU	· 1
and defect) and (imag\$3 with defect)) and EPO; JP	
magnif\$4) and (monitor or screen)) and DERWENT	L L
select\$3) and (select\$3 with area)) and IBM_TDB	
display\$3) and ((mov\$3 or position\$3 or	
adjust\$3) with (sample or stage or wafer	1
or mask or rectile or substrate))) and	
compar\$4) and referenc\$3) and (compar\$4	
with referenc\$3)) and (superimpos\$4 or	
impos\$4)) and stor\$4) and arithmetic	0000/01/10 16 10
106 12 (((((((((((((((((((((((((((((((((((2003/01/12 16:12
electron adj microscop\$3)) and (imag\$3) US-PGPU	
and defect) and (imag\$3 with defect)) and EPO; JP	L L
magnif\$4) and (monitor or screen)) and DERWENT	;
select\$3) and (select\$3 with area)) and IBM_TDB	
display\$3) and ((mov\$3 or position\$3 or	
adjust\$3) with (sample or stage or wafer	
or mask or rectile or substrate))) and	
compar\$4) and referenc\$3) and (compar\$4	
with referenc\$3)) and (superimpos\$4 or	
impos\$4)) and stor\$4) and calculat\$4	2003/01/12 16:12
impos\$4)) and stor\$4) and calculat\$4 113 12 (((((((((((((SEM or (scanning adj USPAT;	
impos\$4)) and stor\$4) and calculat\$4 113 12 (((((((((((((SEM or (scanning adj uSPAT; electron adj microscop\$3)) and (imag\$3) US-PGPU	
impos\$4)) and stor\$4) and calculat\$4 (((((((((((((((((((((((((((((((((((0;
impos\$4)) and stor\$4) and calculat\$4 ((((((((((((((((((((((((((((((((((((o; ;
impos\$4)) and stor\$4) and calculat\$4 ((((((((((((((((((((((((((((((((((((o; ;
impos\$4)) and stor\$4) and calculat\$4 (((((((((((((((((((((((((((((((((((o; ;
impos\$4)) and stor\$4) and calculat\$4 ((((((((((((((((((((((((((((((((((((o; ;
impos\$4)) and stor\$4) and calculat\$4 ((((((((((((((((((((((((((((((((((((o; ;
impos\$4)) and stor\$4) and calculat\$4 (((((((((((((((((((((((((((((((((((o; ;
impos\$4)) and stor\$4) and calculat\$4 (((((((((((((((((((((((((((((((((((o; ;
impos\$4)) and stor\$4) and calculat\$4 (((((((((((((((((((((((((((((((((((o; ;

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120		12	((((((((((((((((((((((((((((((((((((((USPAT; US-PGPUB;	2003/01/12 16:12
			<pre>and defect) and (imag\$3 with defect)) and magnif\$4) and (monitor or screen)) and</pre>	EPO; JPO; DERWENT;	
			select\$3) and (select\$3 with area)) and	IBM TDB	-
			display\$3) and ((mov\$3 or position\$3 or	_	
			adjust\$3) with (sample or stage or wafer		
!	1		or mask or rectile or substrate))) and		
!			<pre>compar\$4) and referenc\$3) and (compar\$4 with referenc\$3)) and (superimpos\$4 or</pre>		
			impos\$4)) and stor\$4) and calculat\$4) and		
			data) and inspect\$5		
127	İ	0	((((((((((((((((((((((((((((((((((((((USPAT;	2003/01/12 16:13
			electron adj microscop\$3)) and (imag\$3) and defect) and (imag\$3 with defect)) and	US-PGPUB; EPO; JPO;	
	182		magnif\$4) and (monitor or screen)) and	DERWENT;	:
			select\$3) and (select\$3 with area)) and	IBM_TDB	
	Î		display\$3) and ((mov\$3 or position\$3 or		
			adjust\$3) with (sample or stage or wafer or mask or rectile or substrate))) and		
			compar\$4) and referenc\$3) and (compar\$4		
			with referenc\$3)) and (superimpos\$4 or		
ı	ì		impos\$4)) and stor\$4) and calculat\$4) and data) and inspect\$5) and ((eras\$4 or		
			remov\$4 or delet\$4) with background)		
134		11	((((((((((((((SEM or (scanning adj	USPAT;	2003/01/12 16:14
			electron adj microscop\$3)) and (imag\$3)	US-PGPUB;	
			and defect) and (imag\$3 with defect)) and magnif\$4) and (monitor or screen)) and	EPO; JPO; DERWENT;	
			select\$3) and (select\$3 with area)) and	IBM TDB	
1			display\$3) and ((mov\$3 or position\$3 or		
	4		adjust\$3) with (sample or stage or wafer		
			or mask or rectile or substrate))) and compar\$4) and referenc\$3) and (compar\$4		
			with referenc\$3)) and (superimpos\$4 or		
			impos\$4)) and stor\$4) and calculat\$4) and		
			data) and inspect\$5) and (eras\$4 or		
141		10	remov\$4 or delet\$4) {(((((((((((((((SEM or (scanning adj	USPAT;	2003/01/12 16:14
141		10	electron adj microscop\$3)) and (imag\$3)	US-PGPUB;	2000,01,12 10.11
			and defect) and (imag\$3 with defect)) and	EPO; JPO;	
			magnif\$4) and (monitor or screen)) and	DERWENT;	
			select\$3) and (select\$3 with area)) and display\$3) and ((mov\$3 or position\$3 or	IBM_TDB	
1			adjust\$3) with (sample or stage or wafer		
			or mask or rectile or substrate))) and		
			compar\$4) and referenc\$3) and (compar\$4 with referenc\$3)) and (superimpos\$4 or		
			impos\$4)) and stor\$4) and calculat\$4) and		
			data) and inspect\$5) and (eras\$4 or		
1			remov\$4 or delet\$4)) and scal\$3	I I C D D III	2002/01/12 16 15
148		10	<pre>((((((((((((((((((((((((((((((((((((</pre>	USPAT; US-PGPUB;	2003/01/12 16:15
:	i I		and defect) and (imag\$3 with defect)) and	EPO; JPO;	
1			magnif\$4) and (monitor or screen)) and	DERWENT;	
			select\$3) and (select\$3 with area)) and	IBM_TDB	
			display\$3) and ((mov\$3 or position\$3 or adjust\$3) with (sample or stage or wafer		
			or mask or rectile or substrate))) and		
			compar\$4) and referenc\$3) and (compar\$4		
1			with referenc\$3)) and (superimpos\$4 or impos\$4)) and stor\$4) and calculat\$4) and		
			data) and inspect\$5) and (eras\$4 or		
			remov\$4 or delet\$4)) and (scale or		
			scaling)		

155	10	((((((((((((((((((((((((((((((((((((((USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/01/12 16:15
162	8	<pre>((((((((((((((((((((((((((((((((((((</pre>	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/01/12 16:28
169	3	((((((((((((((((((((((((((((((((((((((USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/01/12 16:16
176	5	((((((((((((((((((((((((((((((((((((((USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/01/12 16:37

183 0	((((((((((((((((((((((((((((((((((((((USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/01/12	16:38
	((superimpos\$4 or impos\$4) with imag\$4)) and ((two or second or multiple) with screen)			

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